

# ISO/TS 22933:2022-04 (E)

## Surface chemical analysis - Secondary ion mass spectrometry - Method for the measurement of mass resolution in SIMS

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<b>Contents</b>		<b>Page</b>
Foreword .....		iv
Introduction .....		v
1	Scope .....	1
2	Normative references .....	1
3	Terms and definitions .....	1
4	Symbols and abbreviated terms .....	2
5	Definitions of mass resolution based on peak separation of two mass peaks .....	2
5.1	General .....	2
5.2	X% valley .....	2
5.3	X% peak width M (X%) or R (X%) = $M/M(X\%)$ .....	3
5.4	X% peak tail interference .....	4
5.5	Summary .....	4
6	Procedure to determine the mass resolution .....	5
6.1	General .....	5
6.2	Removing contamination on sample surface .....	5
6.3	Obtaining spectrum peak .....	5
6.4	Determination of mass resolution .....	5
7	Mass resolution comparison between different type of SIMS .....	5
7.1	Mass resolution comparison between M-SIMS and TOF-SIMS .....	5
7.2	Mass resolution comparison between TOF-SIMS and FTICR-SIMS .....	7
7.3	Mass resolution of flat top mass peak .....	8
8	Conclusion .....	9
Annex A (informative)	Examples of mass resolution measured by Q-SIMS, TOF-SIMS, Magnetic-SIMS, Orbitrap-SIMS and FTICR-SIMS .....	10
Bibliography .....		15